## Notice of References Cited Application/Control No. 10/604,943 Examiner Dana Shin Applicant(s)/Patent Under Reexamination BENTWICH, ITZHAK Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-			
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## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Odde	Date MM-YYYY	Country	Name	Classification
	N	WO 2005001128 A2 /	01-2005	World Intellect	MOYER et al.	
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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